

<b>Notice of References Cited</b>	Application/Control No. 10/564,402		Applicant(s)/Patent Under Reexamination UKAI ET AL.	
	Examiner GiGi Huang		Art Unit 1618	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0039597	04-2002	UKAI et al.	424/490
*	B	US-6,132,771	10-2000	Depui et al.	424/468
*	C	US-2002/0160046	10-2002	Robinson et al.	424/469
*	D	US-6,749,867	06-2004	Robinson et al.	424/489
*	E	US-2006/0204585	09-2006	Hall et al.	424/489
*	F	US-2005/0042285	02-2005	Ukai et al.	424/464
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 9725066 A1	07-1997	World Intellect	DEPUI et al.	---
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	STG Particle Size/Screen Mesh Comparison, <a href="http://www.wovenwire.com/reference/particle-size-print.htm">http://www.wovenwire.com/reference/particle-size-print.htm</a> , page 1-2
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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